Table 1. Reliability test results

rabio ii itoliability toot rocalic							
Test Items 試験項目	Test conditions 試験条件	Number of samples 試料数	Number of failures 故障数				
Resistance to soldering heat はんだ耐熱性	Solder temperature : 260°C Time : 10seconds	5	0				
Solderability はんだ付け性	Preheating : 100°C Solder temperature : 250°C Time : 10seconds	5	0				
Temperature cycle 温度サイクル	-40℃~125℃ 30minutes each 100cycles	5	0				
Terminal strength(pull) 端子強度(引張り)	Weight 10N 10seconds	5	0				
Terminal strength(Bending) 端子強度(曲げ)	Weight 5N 90deg. Bend 2times	5	0				
Mounting torque 締付けトルク	Mounting screw : M3 0.98N·m	5	0				
High temperature storage 高温保存	T _a =125℃ 1000hours	5	0				
Temperature humidity storage 高温高湿保存	T _a =60℃ RH=90% 1000hours	5	0				
High-Temperature Reverse-Bias 高温逆バイアス	T _j =150°C V _{CE} =0.85*V _{CES} 1000hours	5	0				
Intermittent operating life 断続動作	△T _j =100°C 5000cycles	5	0				

Table 2. Failure criteria

Table 2.1 and 6 of terra						
Parameter	Measurement conditions 測定条件	Criteria for failure 故障判定基準		Remarks 備考		
測定項目		Lower Limit 下限	Upper Limit 上限			
Ices	V _{CE} =Rated voltage	_	U.S.L.×2.0			
V _{EC}	-I _C =Rated current	_	U.S.L.×1.2			
V _{CE(sat)}	I _C =Rated current, V _D =V _{DB} =15V, V _{IN} =5V	_	U.S.L.×1.2			
V_{F}	I _F =10mA including voltage drop by limiting resistor	_	U.S.L.×1.2			
Ι _D	$V_D=15V$, $V_{IN}=0V$	_	U.S.L.×2.0			
I_{DB}	$V_D=V_{DB}=15V$, $V_{IN}=0V$	_	U.S.L.×2.0			
Dielectric withstand	2500Vrms, Sinusoidal, AC 1 minute, all connection pins to heat-sink plate	Break down				

Note: The reliability tests are performed the representative products for the product group.

The measurement items of each test are selected according to our standards.

The symbols in the table are as follows. U.S.L.: Upper Specification Limit

Publication Date: Nov. 2023

Keep safety first in your circuit designs!

Mitsubishi Electric Corporation puts the maximum effort into making semiconductor products better and more reliable, but there is always the possibility that trouble may occur with them. Trouble with semiconductors may lead to personal injury, fire or property damage. Remember to give due consideration to safety when making your circuit designs, with appropriate measures such as (i) safety margin, (ii)placement of substitutive, auxiliary circuits, (iii)use of non-flammable material or (iv) prevention against any malfunction or mishap. Before the adoption of semiconductor products, the reference to individual application notes is recommended.

Mitsubishi Electric Corporation assumes no responsibility for any damage with customer safety design deficiency and/or usage of outrange of specification.

Notes regarding these materials

- •These materials are intended as a reference to assist our customers in the selection of the Mitsubishi semiconductor product best suited to the customer's application; they do not convey any license under any intellectual property rights, or any other rights, belonging to Mitsubishi Electric Corporation or a third party.
- •Mitsubishi Electric Corporation assumes no responsibility for any damage, or infringement of any third-party's rights, originating in the use of any product data, diagrams, charts, programs, algorithms, or circuit application examples contained in these materials.
- •All information contained in these materials, including product data, diagrams, charts, programs and algorithms represents information on products at the time of publication of these materials, and are subject to change by Mitsubishi Electric Corporation without notice due to product improvements or other reasons. It is therefore recommended that customers contact Mitsubishi Electric Corporation or an authorized Mitsubishi Semiconductor product distributor for the latest product information before purchasing a product listed herein.

The information described here may contain technical inaccuracies or typographical errors. Mitsubishi Electric Corporation assumes no responsibility for any damage, liability, or other loss rising from these inaccuracies or errors.

Please also pay attention to information published by Mitsubishi Electric Corporation by various means, including the Mitsubishi Semiconductor home page (https://www.mitsubishielectric.com/semiconductors/powerdevices/).

- •When using any or all of the information contained in these materials, including product data, diagrams, charts, programs, and algorithms, please be sure to evaluate all information as a total system before making a final decision on the applicability of the information and products. Mitsubishi Electric Corporation assumes no responsibility for any damage, liability or other loss resulting from the information contained herein.
- •Mitsubishi Electric Corporation semiconductors are not designed or manufactured for use in a device or system that is used under circumstances in which human life is potentially at stake. Please contact Mitsubishi Electric Corporation or an authorized Mitsubishi Semiconductor product distributor when considering the use of a product contained herein for any specific purposes, such as apparatus or systems for transportation, vehicular, medical, aerospace, nuclear, or undersea repeater use.
- •The prior written approval of Mitsubishi Electric Corporation is necessary to reprint or reproduce in whole or in part these materials.
- •If these products or technologies are subject to the Japanese export control restrictions, they must be exported under a license from the Japanese government and cannot be imported into a country other than the approved destination.

Any diversion or re-export contrary to the export control laws and regulations of Japan and/or the country of destination is prohibited.

•Please contact Mitsubishi Electric Corporation or an authorized Mitsubishi Semiconductor product distributor for further details on these materials or the products contained therein.

© MITSUBISHI ELECTRIC CORPORATION. ALL RIGHTS RESERVED. DIPIPM are trademarks of MITSUBISHI ELECTRIC CORPORATION.

Publication Date: Nov. 2023